

2007 International Image Sensor Workshop Participants

First Name	Last Name	Affiliation
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Salman	Akram	Micron Technology Inc, USA
Juha	Alakarhu	Nokia, Finland
Hiroaki	Ammo	Sony Corporation, Japan
Bernard	Aspar	SOITEC, France
Thomas	Baechler	CSEM, Switzerland
Alex	Belenky	Ben-Gurion University of Negev, Israel
Morley	Blouke	Ball Aerospace and Technology Corporation, USA
Jan	Bosiers	DALSA Corporation, The Netherlands
Richard	Bredthauer	Semiconductor Technology Associates, Canada
Barry	Burke	MIT Lincoln Laboratory, USA
Sophie	Caranhac	E2V, France
Peter	Centen	Grass Valley, The Netherlands
Chung-Wei	Chang	TSMC, ROC
Eduardo	Charbon	EPFL, Switzerland
Ho-Ching	Chien	PixArt Imaging Inc., ROC
Soodong	Cho	Clairpixel Company Ltd, Korea
Kwang-Bo	Cho	Micron Technology Inc., USA
Seong-Ho	Cho	Samsung Electronics Company Ltd., Korea
Thomas	Cunningham	Jet Propulsion Laboratory, USA
Tiejun	Dai	OmniVision Technologies Inc., USA
Tobi	Delbruck	UNI-ETH Zurich, Switzerland
Donal	Denvir	Andor Technology, UK
Grzegorz	Deptuch	Brookhaven Laboratory, USA
Bart	Dierickx	Caeleste; IMEC, Belgium
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N	Egami	NHK Science & Technical Research Labs, Japan
John	Ellis-Monaghan	IBM, USA
Keith	Findlater	Gigle Semiconductor, UK
Eric	Fossum	Siimpel Corporation, USA
Boyd	Fowler	Fairchild Imaging Inc., USA
Eric	Fox	DALSA Corporation, Canada
Hiraoki	Fujita	Eastman Kodak Company, USA
Jeff	Gambino	IBM, USA
Arie	Gavriely	Advasense Technologies, Israel
Alexander	Getman	Samsung Electronics Company Ltd., Korea
Terry	Gilton	Micron Technology Inc., USA
Lindsay	Grant	ST Microelectronics, UK
Tomas	Guerts	Cypress Semiconductor, Belgium
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Homayoon	Haddad	Magnachip Semiconductor, USA
Takayuki	Hamamoto	Tokyo University of Science, Japan
Hyung-Jun	Han	MagnaChip, Korea
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Nobuhiro	Karasawa	Sony Corporation, Japan
Shoji	Kawahito	Shizuoka University, Japan
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Daebyung	Kim	Magnachip Semiconductor, Korea
Bumsuk	Kim	Samsung Electronics Company Ltd., Korea
DongSoo	Kim	Yonsei University, Korea
Yoshiaki	Kitano	Sony Corporation, Japan
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Alex	Krymski	Alexima, USA
Yoshihisa	Kunimi	Asahi Kasei EMD Corporation, Japan
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Paul	Lee	ITT, USA
Jeonghwan	Lee	Yonsei University, Korea
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Younsub	Lim	Magnachip Semiconductor, Korea
Chiao	Liu	Fairchild Imaging Inc., USA
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Guy	Meynants	Stichting IMEC-NL, Belgium
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Haruhiko	Murata	Sanyo Electric Company Ltd., Japan
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Junichi	Nakamura	Micron Japan Ltd., Japan
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